

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V.		User Part Number					
		PMEG60T10ELXD-Q					
Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		Part Description					
		Nexperia DHAM					
		SMD package					
		Test Conditions	Duration	# Lots	# Quantity	# Rejects	
	TEST						
	Pre- and Post-Stress						
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
		JESD22-A113					
		Bake Tamb = 125 °C	24 hours				
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours				
# A1	Preconditioning	Reflow soldering	3 cycles	1514	64430	0	
		MIL-STD-750-1					
	HTRB	M1038 Method A					
	High Temperature Reverse	Tj = Tjmax, Vr = 100% of max. datasheet					
# B1	Bias	reverse voltage ^[1]	1000 hours	206	9320	0	
	тс	JESD22-A104					
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	311	14080	0	
	UHAST	JESD22-A118					
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %					
+ A3 01	Olibiased HAST	· · · · · · · · · · · · · · · · · · ·	- 96 hours	311	14080	0	
	•6	JESD22-A102					
# A2 - It	AC Autoclave	Tamb = 121 °C, RH = 100 % Pressure = 205 kPa (29.7 psia)					
# A3 alt	Autociave	riessule = 203 kra (29.7 psia)					
	H3TRB	JESD22-A101					
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of					
# A2 alt		rated reverse voltage ^{[1], [2]}	1000 hours	311	14080	0	
# AZ dit	peracare recreise blus	MIL-STD-750 Method 1037	1000 110015	311	1 1000		
	IOL	ton = toff, devices powered to insure ΔT_i =					
# A5	Intermittent Operating Life		1000 hours	312	14120	0	
, ,,,	2commeteric Operating Life	200 2.0. 15000 Cycles	1000 110015	J12	17120		
	RSH	JESD22-A111					
# C8	Resistance to Solder Heat		10 s	269	8070	0	
			200	_0,	00.0	-	
	SD						

^[1] The physical limitations of Schottky diodes have to be considered (thermal runaway).

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Schottky	9320	0	0,46	2,19E+09

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^[2] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.